

Notice of References Cited

Application/Control No.

10/021,692

Applicant(s)/Patent Under
Reexamination
KIPP ET AL.

Examiner

Simon J. Oh

Art Unit

1615

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5174930	12-1992	Stainmesse et al.	264/4.6
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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